

<b>Notice of References Cited</b>		Application/Control No. 10/585,067	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
		Examiner NICOLE M. BUIE-HATCHER	Art Unit 1796	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

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	U	translation of Savinkin et al. (RU 2164524 C1), 12/24/2009
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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